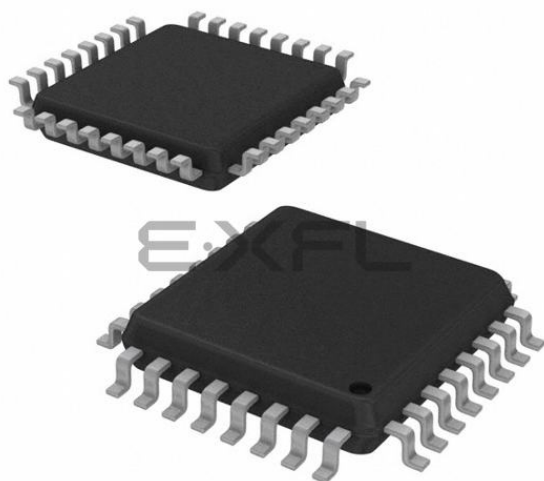




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Details

Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I ² C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, IR, POR, PWM, WDT
Number of I/O	30
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 22x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8l151k6t3

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and STM8L152x4/6 devices, the acquisition sequence is managed by software and it involves analog I/O groups and the routing interface.

Reliable touch sensing solutions can be quickly and easily implemented using the free STM8 Touch Sensing Library.

3.14 Timers

Medium-density STM8L151x4/6 and STM8L152x4/6 devices contain one advanced control timer (TIM1), two 16-bit general purpose timers (TIM2 and TIM3) and one 8-bit basic timer (TIM4).

All the timers can be served by DMA1.

[Table 3](#) compares the features of the advanced control, general-purpose and basic timers.

Table 3. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA1 request generation	Capture/compare channels	Complementary outputs
TIM1	16-bit	up/down	Any integer from 1 to 65536	Yes	3 + 1	3
TIM2			Any power of 2 from 1 to 128		2	None
TIM3						
TIM4	8-bit	up	Any power of 2 from 1 to 32768		0	

3.14.1 TIM1 - 16-bit advanced control timer

This is a high-end timer designed for a wide range of control applications. With its complementary outputs, dead-time control and center-aligned PWM capability, the field of applications is extended to motor control, lighting and half-bridge driver.

- 16-bit up, down and up/down autoreload counter with 16-bit prescaler
- 3 independent capture/compare channels (CAPCOM) configurable as input capture, output compare, PWM generation (edge and center aligned mode) and single pulse mode output
- 1 additional capture/compare channel which is not connected to an external I/O
- Synchronization module to control the timer with external signals
- Break input to force timer outputs into a defined state
- 3 complementary outputs with adjustable dead time
- Encoder mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)

3.19 Development support

Development tools

Development tools for the STM8 microcontrollers include:

- The STice emulation system offering tracing and code profiling
- The STVD high-level language debugger including C compiler, assembler and integrated development environment
- The STVP Flash programming software

The STM8 also comes with starter kits, evaluation boards and low-cost in-circuit debugging/programming tools.

Single wire data interface (SWIM) and debug module

The debug module with its single wire data interface (SWIM) permits non-intrusive real-time in-circuit debugging and fast memory programming.

The single-wire interface is used for direct access to the debugging module and memory programming. The interface can be activated in all device operation modes.

The non-intrusive debugging module features a performance close to a full-featured emulator. Beside memory and peripherals, CPU operation can also be monitored in real-time by means of shadow registers.

Bootloader

A bootloader is available to reprogram the Flash memory using the USART1 interface. The reference document for the bootloader is *UM0560: STM8 bootloader user manual*.

Table 4. Legend/abbreviation for table 5

Type	I= input, O = output, S = power supply	
Level	FT	Five-volt tolerant
	TT	3.6 V tolerant
	Output	HS = high sink/source (20 mA)
Port and control configuration	Input	float = floating, wpu = weak pull-up
	Output	T = true open drain, OD = open drain, PP = push pull
Reset state	Bold X (pin state after reset release). Unless otherwise specified, the pin state is the same during the reset phase (i.e. "under reset") and after internal reset release (i.e. at reset state).	

Table 5. Medium-density STM8L151x4/6, STM8L152x4/6 pin description

Pin number				Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP48/UFQFPN48	LQFP32/UFQFPN32	UFQFPN28	WLCSP28				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
2	1	1	C3	NRST/PA1 ⁽¹⁾	I/O			X		HS		X	Reset	PA1
3	2	2	B4	PA2/OSC_IN/ [USART1_TX] ⁽⁴⁾ / [SPI1_MISO] ⁽⁴⁾	I/O		X	X	X	HS	X	X	Port A2	HSE oscillator input / [USART1 transmit] / [SPI1 master in- slave out] /
4	3	3	C4	PA3/OSC_OUT/[USART1_RX] ⁽⁴⁾ / [SPI1_MOSI] ⁽⁴⁾	I/O		X	X	X	HS	X	X	Port A3	HSE oscillator output / [USART1 receive] / [SPI1 master out/slave in] /
5	-	-	-	PA4/TIM2_BKIN/ LCD_COM0 ⁽²⁾ /ADC1_IN2/ COMP1_INP	I/O	TT ₍₃₎	X	X	X	HS	X	X	Port A4	Timer 2 - break input / LCD_COM 0 / ADC1 input 2 / Comparator 1 positive input
-	4	4	D3	PA4/TIM2_BKIN/ [TIM2_ETR] ⁽⁴⁾ / LCD_COM0 ⁽²⁾ / ADC1_IN2/COMP1_INP	I/O	TT ₍₃₎	X	X	X	HS	X	X	Port A4	Timer 2 - break input / [Timer 2 - external trigger] / LCD_COM 0 / ADC1 input 2 / Comparator 1 positive input
6	-	-	-	PA5/TIM3_BKIN/ LCD_COM1 ⁽²⁾ /ADC1_IN1/ COMP1_INP	I/O	TT ₍₃₎	X	X	X	HS	X	X	Port A5	Timer 3 - break input / LCD_COM 1 / ADC1 input 1/ Comparator 1 positive input

Table 5. Medium-density STM8L151x4/6, STM8L152x4/6 pin description (continued)

Pin number				Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP48/UFQFPN48	LQFP32/UFQFPN32	UFQFPN28	WLCSP28				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
-	5	5	D4	PA5/TIM3_BKIN/ [TIM3_ETR] ⁽⁴⁾ / LCD_COM1 ⁽²⁾ /ADC1_IN1/ COMP1_INP	I/O	TT (3)	X	X	X	HS	X	X	Port A5	Timer 3 - break input / [Timer 3 - external trigger] / LCD_COM 1 / ADC1 input 1 / Comparator 1 positive input
7	6	-	-	PA6/[ADC1_TRIG] ⁽⁴⁾ / LCD_COM2 ⁽²⁾ /ADC1_IN0/ COMP1_INP	I/O	TT (3)	X	X	X	HS	X	X	Port A6	[ADC1 - trigger] / LCD_COM2 / ADC1 input 0 / Comparator 1 positive input
8	-	-	-	PA7/LCD_SEG0 ⁽²⁾⁽⁵⁾	I/O	FT	X	X	X	HS	X	X	Port A7	LCD segment 0
24	13	12	E3	PB0 ⁽⁶⁾ /TIM2_CH1/ LCD_SEG10 ⁽²⁾ / ADC1_IN18/COMP1_INP	I/O	TT (3)	X ⁽⁶⁾	X ⁽⁶⁾	X	HS	X	X	Port B0	Timer 2 - channel 1 / LCD segment 10 / ADC1_IN18 / Comparator 1 positive input
25	14	13	G1	PB1/TIM3_CH1/ LCD_SEG11 ⁽²⁾ / ADC1_IN17/COMP1_INP	I/O	TT (3)	X	X	X	HS	X	X	Port B1	Timer 3 - channel 1 / LCD segment 11 / ADC1_IN17 / Comparator 1 positive input
26	15	14	F2	PB2/ TIM2_CH2/ LCD_SEG12 ⁽²⁾ / ADC1_IN16/COMP1_INP	I/O	TT (3)	X	X	X	HS	X	X	Port B2	Timer 2 - channel 2 / LCD segment 12 / ADC1_IN16/ Comparator 1 positive input
27	-	-	-	PB3/TIM2_ETR/ LCD_SEG13 ⁽²⁾ / ADC1_IN15/COMP1_INP	I/O	TT (3)	X	X	X	HS	X	X	Port B3	Timer 2 - external trigger / LCD segment 13 /ADC1_IN15 / Comparator 1 positive input

Table 8. I/O port hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 500A	Port C	PC_ODR	Port C data output latch register	0x00
0x00 500B		PC_IDR	Port C input pin value register	0xFF
0x00 500C		PC_DDR	Port C data direction register	0x00
0x00 500D		PC_CR1	Port C control register 1	0x00
0x00 500E		PC_CR2	Port C control register 2	0x00
0x00 500F	Port D	PD_ODR	Port D data output latch register	0x00
0x00 5010		PD_IDR	Port D input pin value register	0xFF
0x00 5011		PD_DDR	Port D data direction register	0x00
0x00 5012		PD_CR1	Port D control register 1	0x00
0x00 5013		PD_CR2	Port D control register 2	0x00
0x00 5014	Port E	PE_ODR	Port E data output latch register	0x00
0x00 5015		PE_IDR	Port E input pin value register	0xFF
0x00 5016		PE_DDR	Port E data direction register	0x00
0x00 5017		PE_CR1	Port E control register 1	0x00
0x00 5018		PE_CR2	Port E control register 2	0x00
0x00 5019	Port F	PF_ODR	Port F data output latch register	0x00
0x00 501A		PF_IDR	Port F input pin value register	0xFF
0x00 501B		PF_DDR	Port F data direction register	0x00
0x00 501C		PF_CR1	Port F control register 1	0x00
0x00 501D		PF_CR2	Port F control register 2	0x00

Table 9. General hardware register map

Address	Block	Register label	Register name	Reset status
0x00 501E to 0x00 5049	Reserved area (28 bytes)			
0x00 5050	Flash	FLASH_CR1	Flash control register 1	0x00
0x00 5051		FLASH_CR2	Flash control register 2	0x00
0x00 5052		FLASH_PUKR	Flash program memory unprotection key register	0x00
0x00 5053		FLASH_DUKR	Data EEPROM unprotection key register	0x00
0x00 5054		FLASH_IAPSR	Flash in-application programming status register	0x00

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5055 to 0x00 506F	Reserved area (27 bytes)			
0x00 5070	DMA1	DMA1_GCSR	DMA1 global configuration & status register	0xFC
0x00 5071		DMA1_GIR1	DMA1 global interrupt register 1	0x00
0x00 5072 to 0x00 5074		Reserved area (3 bytes)		
0x00 5075		DMA1_C0CR	DMA1 channel 0 configuration register	0x00
0x00 5076		DMA1_C0SPR	DMA1 channel 0 status & priority register	0x00
0x00 5077		DMA1_C0NDTR	DMA1 number of data to transfer register (channel 0)	0x00
0x00 5078		DMA1_C0PARH	DMA1 peripheral address high register (channel 0)	0x52
0x00 5079		DMA1_C0PARL	DMA1 peripheral address low register (channel 0)	0x00
0x00 507A		Reserved area (1 byte)		
0x00 507B		DMA1_C0M0ARH	DMA1 memory 0 address high register (channel 0)	0x00
0x00 507C		DMA1_C0M0ARL	DMA1 memory 0 address low register (channel 0)	0x00
0x00 507D to 0x00 507E		Reserved area (2 bytes)		
0x00 507F		DMA1_C1CR	DMA1 channel 1 configuration register	0x00
0x00 5080		DMA1_C1SPR	DMA1 channel 1 status & priority register	0x00
0x00 5081		DMA1_C1NDTR	DMA1 number of data to transfer register (channel 1)	0x00
0x00 5082		DMA1_C1PARH	DMA1 peripheral address high register (channel 1)	0x52
0x00 5083		DMA1_C1PARL	DMA1 peripheral address low register (channel 1)	0x00

Table 10. CPU/SWIM/debug module/interrupt controller registers

Address	Block	Register Label	Register Name	Reset Status
0x00 7F00	CPU ⁽¹⁾	A	Accumulator	0x00
0x00 7F01		PCE	Program counter extended	0x00
0x00 7F02		PCH	Program counter high	0x00
0x00 7F03		PCL	Program counter low	0x00
0x00 7F04		XH	X index register high	0x00
0x00 7F05		XL	X index register low	0x00
0x00 7F06		YH	Y index register high	0x00
0x00 7F07		YL	Y index register low	0x00
0x00 7F08		SPH	Stack pointer high	0x03
0x00 7F09		SPL	Stack pointer low	0xFF
0x00 7F0A		CCR	Condition code register	0x28
0x00 7F0B to 0x00 7F5F	CPU	Reserved area (85 byte)		
0x00 7F60		CFG_GCR	Global configuration register	0x00
0x00 7F70	ITC-SPR	ITC_SPR1	Interrupt Software priority register 1	0xFF
0x00 7F71		ITC_SPR2	Interrupt Software priority register 2	0xFF
0x00 7F72		ITC_SPR3	Interrupt Software priority register 3	0xFF
0x00 7F73		ITC_SPR4	Interrupt Software priority register 4	0xFF
0x00 7F74		ITC_SPR5	Interrupt Software priority register 5	0xFF
0x00 7F75		ITC_SPR6	Interrupt Software priority register 6	0xFF
0x00 7F76		ITC_SPR7	Interrupt Software priority register 7	0xFF
0x00 7F77		ITC_SPR8	Interrupt Software priority register 8	0xFF
0x00 7F78 to 0x00 7F79	Reserved area (2 byte)			
0x00 7F80	SWIM	SWIM_CSR	SWIM control status register	0x00
0x00 7F81 to 0x00 7F8F	Reserved area (15 byte)			

Table 20. Total current consumption in Run mode

Symbol	Parameter	Conditions ⁽¹⁾			Typ	Max				Unit
						55 °C	85 °C ⁽²⁾	105 °C ⁽³⁾	125 °C ⁽⁴⁾	
$I_{DD(RUN)}$	Supply current in run mode ⁽⁵⁾	All peripherals OFF, code executed from RAM, V_{DD} from 1.65 V to 3.6 V	HSI RC osc. (16 MHz) ⁽⁶⁾	$f_{CPU} = 125 \text{ kHz}$	0.39	0.47	0.49	0.52	0.55	mA
				$f_{CPU} = 1 \text{ MHz}$	0.48	0.56	0.58	0.61	0.65	
				$f_{CPU} = 4 \text{ MHz}$	0.75	0.84	0.86	0.91	0.99	
				$f_{CPU} = 8 \text{ MHz}$	1.10	1.20	1.25	1.31	1.40	
				$f_{CPU} = 16 \text{ MHz}$	1.85	1.93	2.12 ⁽⁸⁾	2.29 ⁽⁸⁾	2.36 ⁽⁸⁾	
			HSE external clock ($f_{CPU}=f_{HSE}$) ⁽⁷⁾	$f_{CPU} = 125 \text{ kHz}$	0.05	0.06	0.09	0.11	0.12	
				$f_{CPU} = 1 \text{ MHz}$	0.18	0.19	0.20	0.22	0.23	
				$f_{CPU} = 4 \text{ MHz}$	0.55	0.62	0.64	0.71	0.77	
				$f_{CPU} = 8 \text{ MHz}$	0.99	1.20	1.21	1.22	1.24	
				$f_{CPU} = 16 \text{ MHz}$	1.90	2.22	2.23 ⁽⁸⁾	2.24 ⁽⁸⁾	2.28 ⁽⁸⁾	
			LSI RC osc. (typ. 38 kHz)	$f_{CPU} = f_{LSI}$	0.040	0.045	0.046	0.048	0.050	
			LSE external clock (32.768 kHz)	$f_{CPU} = f_{LSE}$	0.035	0.040	0.048 ⁽⁸⁾	0.050	0.062	
$I_{DD(RUN)}$	Supply current in Run mode	All peripherals OFF, code executed from Flash, V_{DD} from 1.65 V to 3.6 V	HSI RC osc. ⁽⁹⁾	$f_{CPU} = 125 \text{ kHz}$	0.43	0.55	0.56	0.58	0.62	mA
				$f_{CPU} = 1 \text{ MHz}$	0.60	0.77	0.80	0.82	0.87	
				$f_{CPU} = 4 \text{ MHz}$	1.11	1.34	1.37	1.39	1.43	
				$f_{CPU} = 8 \text{ MHz}$	1.90	2.20	2.23	2.31	2.40	
				$f_{CPU} = 16 \text{ MHz}$	3.8	4.60	4.75	4.87	4.88	
			HSE external clock ($f_{CPU}=f_{HSE}$) ⁽⁷⁾	$f_{CPU} = 125 \text{ kHz}$	0.30	0.36	0.39	0.44	0.47	
				$f_{CPU} = 1 \text{ MHz}$	0.40	0.50	0.52	0.55	0.56	
				$f_{CPU} = 4 \text{ MHz}$	1.15	1.31	1.40	1.45	1.48	
				$f_{CPU} = 8 \text{ MHz}$	2.17	2.33	2.44	2.56	2.77	
				$f_{CPU} = 16 \text{ MHz}$	4.0	4.46	4.52	4.59	4.77	
			LSI RC osc.	$f_{CPU} = f_{LSI}$	0.110	0.123	0.130	0.140	0.150	
			LSE ext. clock (32.768 kHz) ⁽¹⁰⁾	$f_{CPU} = f_{LSE}$	0.100	0.101	0.104	0.119	0.122	

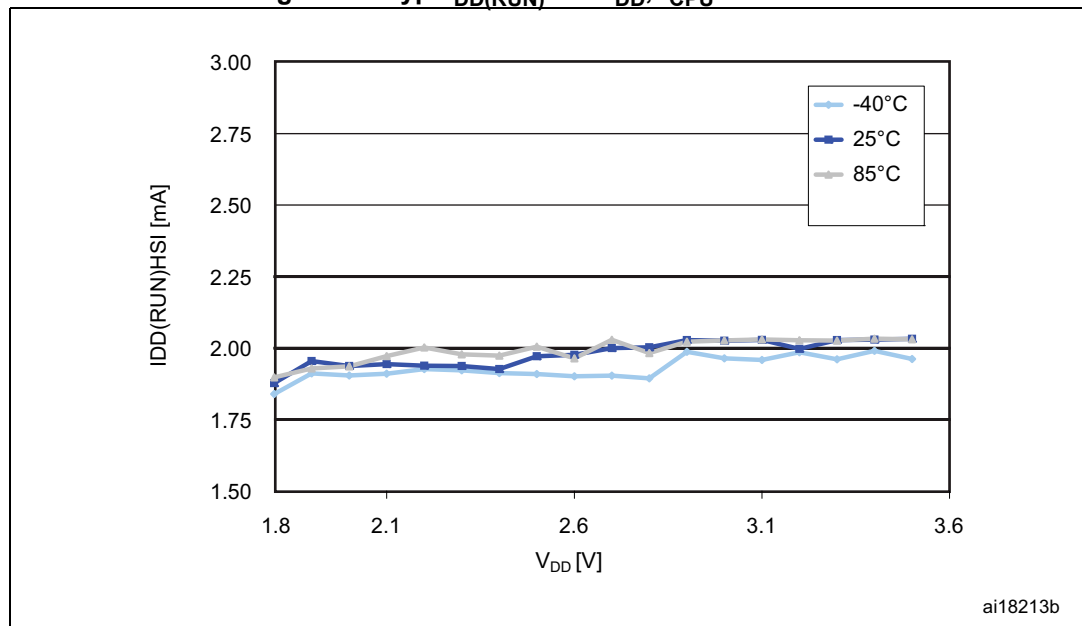
1. All peripherals OFF, V_{DD} from 1.65 V to 3.6 V, HSI internal RC osc., $f_{CPU}=f_{SYSCCLK}$

2. For devices with suffix 6

3. For devices with suffix 7

4. For devices with suffix 3

5. CPU executing typical data processing
6. The run from RAM consumption can be approximated with the linear formula:
 $I_{DD}(\text{run_from_RAM}) = \text{Freq} * 90 \mu\text{A/MHz} + 380 \mu\text{A}$
7. Oscillator bypassed (HSEBYP = 1 in CLK_ECKCR). When configured for external crystal, the HSE consumption ($I_{DD \text{ HSE}}$) must be added. Refer to [Table 31](#).
8. Tested in production.
9. The run from Flash consumption can be approximated with the linear formula:
 $I_{DD}(\text{run_from_Flash}) = \text{Freq} * 195 \mu\text{A/MHz} + 440 \mu\text{A}$
10. Oscillator bypassed (LSEBYP = 1 in CLK_ECKCR). When configured for external crystal, the LSE consumption ($I_{DD \text{ LSE}}$) must be added. Refer to [Table 32](#).

Figure 13. Typ. $I_{DD}(\text{RUN})$ vs. V_{DD} , $f_{\text{CPU}} = 16 \text{ MHz}$ 

1. Typical current consumption measured with code executed from RAM

Table 28. Current consumption under external reset

Symbol	Parameter	Conditions		Typ	Unit
I _{DD(RST)}	Supply current under external reset ⁽¹⁾	All pins are externally tied to V _{DD}	V _{DD} = 1.8 V	48	μA
			V _{DD} = 3 V	76	
			V _{DD} = 3.6 V	91	

1. All pins except PA0, PB0 and PB4 are floating under reset. PA0, PB0 and PB4 are configured with pull-up under reset.

9.3.4 Clock and timing characteristics

HSE external clock (HSEBYP = 1 in CLK_ECKCR)

Subject to general operating conditions for V_{DD} and T_A .

Table 29. HSE external clock characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSE_ext}	External clock source frequency ⁽¹⁾	-	1	-	16	MHz
V_{HSEH}	OSC_IN input pin high level voltage		$0.7 \times V_{DD}$	-	V_{DD}	V
V_{HSEL}	OSC_IN input pin low level voltage		V_{SS}	-	$0.3 \times V_{DD}$	
$C_{in(HSE)}$	OSC_IN input capacitance ⁽¹⁾	-	-	2.6	-	pF
I_{LEAK_HSE}	OSC_IN input leakage current	$V_{SS} < V_{IN} < V_{DD}$	-	-	± 1	μA

1. Data guaranteed by design.

LSE external clock (LSEBYP=1 in CLK_ECKCR)

Subject to general operating conditions for V_{DD} and T_A .

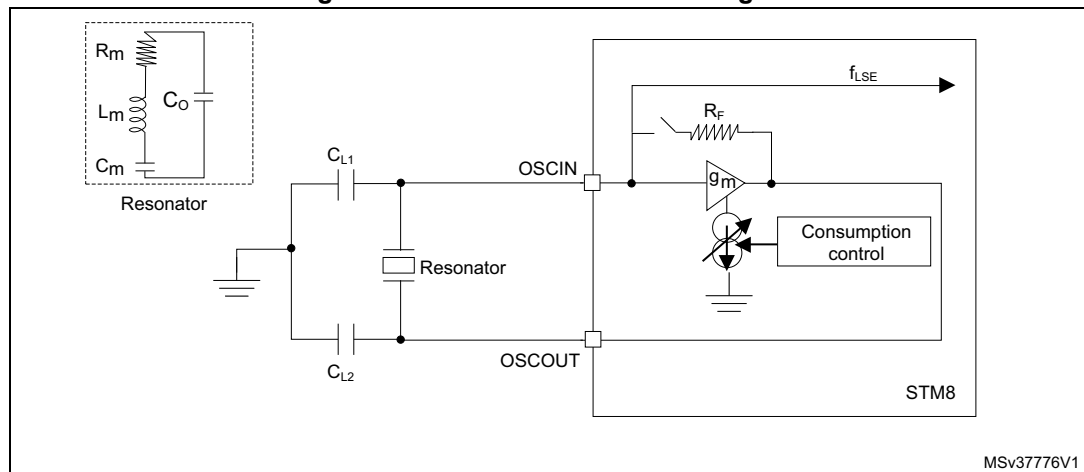
Table 30. LSE external clock characteristics

Symbol	Parameter	Min	Typ	Max	Unit
f_{LSE_ext}	External clock source frequency ⁽¹⁾	-	32.768	-	kHz
$V_{LSEH}^{(2)}$	OSC32_IN input pin high level voltage	$0.7 \times V_{DD}$	-	V_{DD}	V
$V_{LSEL}^{(2)}$	OSC32_IN input pin low level voltage	V_{SS}	-	$0.3 \times V_{DD}$	
$C_{in(LSE)}$	OSC32_IN input capacitance ⁽¹⁾	-	0.6	-	pF
I_{LEAK_LSE}	OSC32_IN input leakage current	-	-	± 1	μA

1. Data guaranteed by design.

2. Data based on characterization results.

Figure 18. LSE oscillator circuit diagram



Internal clock sources

Subject to general operating conditions for V_{DD} , and T_A .

High speed internal RC oscillator (HSI)

In the following table, data is based on characterization results, not tested in production, unless otherwise specified.

Table 33. HSI oscillator characteristics

Symbol	Parameter	Conditions ⁽¹⁾	Min	Typ	Max	Unit
f_{HSI}	Frequency	$V_{DD} = 3.0 \text{ V}$	-	16	-	MHz
ACC_{HSI}	Accuracy of HSI oscillator (factory calibrated)	$V_{DD} = 3.0 \text{ V}, T_A = 25^\circ \text{C}$	-1 ⁽²⁾	-	1 ⁽²⁾	%
		$V_{DD} = 3.0 \text{ V}, 0^\circ \text{C} \leq T_A \leq 55^\circ \text{C}$	-1.5	-	1.5	%
		$V_{DD} = 3.0 \text{ V}, -10^\circ \text{C} \leq T_A \leq 70^\circ \text{C}$	-2	-	2	%
		$V_{DD} = 3.0 \text{ V}, -10^\circ \text{C} \leq T_A \leq 85^\circ \text{C}$	-2.5	-	2	%
		$V_{DD} = 3.0 \text{ V}, -10^\circ \text{C} \leq T_A \leq 125^\circ \text{C}$	-4.5	-	2	%
		$1.65 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}, -40^\circ \text{C} \leq T_A \leq 125^\circ \text{C}$	-4.5	-	3	%
TRIM	HSI user trimming step ⁽³⁾	Trimming code $\neq$ multiple of 16	-	0.4	0.7	%
		Trimming code = multiple of 16	-		± 1.5	%
$t_{su(HSI)}$	HSI oscillator setup time (wakeup time)	-	-	3.7	6 ⁽⁴⁾	μs
$I_{DD(HSI)}$	HSI oscillator power consumption	-	-	100	140 ⁽⁴⁾	μA

1. $V_{DD} = 3.0 \text{ V}$, $T_A = -40$ to 125°C unless otherwise specified.

2. Tested in production.

3. The trimming step differs depending on the trimming code. It is usually negative on the codes which are multiples of 16 (0x00, 0x10, 0x20, 0x30...0xE0). Refer to the AN3101 "STM8L15x internal RC oscillator calibration" application note for more details.

4. Guaranteed by design.

9.3.8 Communication interfaces

SPI1 - Serial peripheral interface

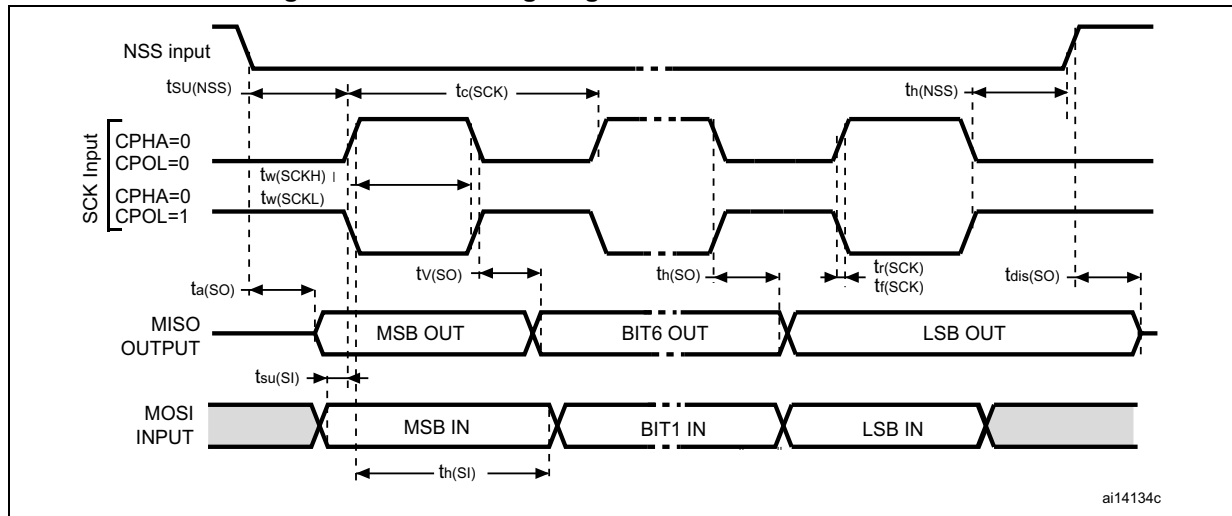
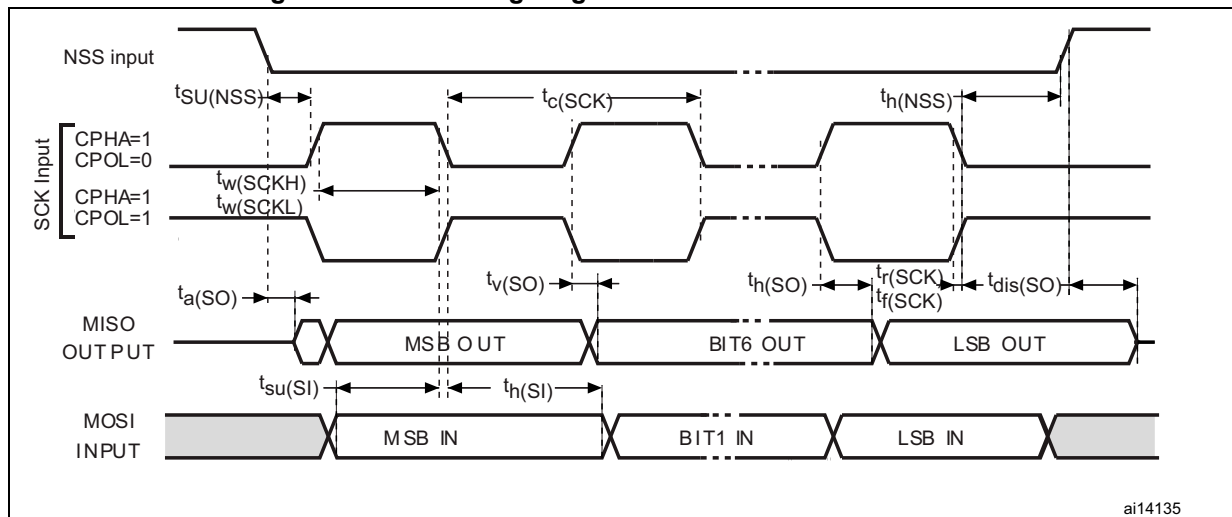
Unless otherwise specified, the parameters given in [Table 43](#) are derived from tests performed under ambient temperature, f_{SYSCLK} frequency and V_{DD} supply voltage conditions summarized in [Section 9.3.1](#). Refer to I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Table 43. SPI1 characteristics

Symbol	Parameter	Conditions ⁽¹⁾	Min	Max	Unit
f_{SCK} $1/t_{\text{c(SCK)}}$	SPI1 clock frequency	Master mode	0	8	MHz
		Slave mode	0	8	
$t_{\text{r(SCK)}}$ $t_{\text{f(SCK)}}$	SPI1 clock rise and fall time	Capacitive load: C = 30 pF	-	30	ns
$t_{\text{su(NSS)}}^{(2)}$	NSS setup time	Slave mode	$4 \times 1/f_{\text{SYSCLK}}$	-	
$t_{\text{h(NSS)}}^{(2)}$	NSS hold time	Slave mode	80	-	
$t_{\text{w(SCKH)}}^{(2)}$ $t_{\text{w(SCKL)}}^{(2)}$	SCK high and low time	Master mode, $f_{\text{MASTER}} = 8 \text{ MHz}$, $f_{\text{SCK}} = 4 \text{ MHz}$	105	145	
$t_{\text{su(MI)}}^{(2)}$ $t_{\text{su(SI)}}^{(2)}$	Data input setup time	Master mode	30	-	
		Slave mode	3	-	
$t_{\text{h(MI)}}^{(2)}$ $t_{\text{h(SI)}}^{(2)}$	Data input hold time	Master mode	15	-	
		Slave mode	0	-	
$t_{\text{a(SO)}}^{(2)(3)}$	Data output access time	Slave mode	-	$3 \times 1/f_{\text{SYSCLK}}$	
$t_{\text{dis(SO)}}^{(2)(4)}$	Data output disable time	Slave mode	30	-	
$t_{\text{v(SO)}}^{(2)}$	Data output valid time	Slave mode (after enable edge)	-	60	
$t_{\text{v(MO)}}^{(2)}$	Data output valid time	Master mode (after enable edge)	-	20	
$t_{\text{h(SO)}}^{(2)}$	Data output hold time	Slave mode (after enable edge)	15	-	
$t_{\text{h(MO)}}^{(2)}$		Master mode (after enable edge)	1	-	

- Parameters are given by selecting 10 MHz I/O output frequency.
- Values based on design simulation and/or characterization results.
- Min time is for the minimum time to drive the output and max time is for the maximum time to validate the data.
- Min time is for the minimum time to invalidate the output and max time is for the maximum time to put the data in Hi-Z.

Figure 34. SPI1 timing diagram - slave mode and CPHA=0

Figure 35. SPI1 timing diagram - slave mode and CPHA=1⁽¹⁾

1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

9.3.14 12-bit ADC1 characteristics

In the following table, data is guaranteed by design, not tested in production.

Table 53. ADC1 characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage	-	1.8	-	3.6	V
V_{REF+}	Reference supply voltage	$2.4\text{ V} \leq V_{DDA} \leq 3.6\text{ V}$	2.4	-	V_{DDA}	V
		$1.8\text{ V} \leq V_{DDA} \leq 2.4\text{ V}$	V_{DDA}			V
V_{REF-}	Lower reference voltage	-	V_{SSA}			V
I_{VDDA}	Current on the V_{DDA} input pin	-	-	1000	1450	μA
I_{VREF+}	Current on the V_{REF+} input pin	-	-	400	700 (peak) ⁽¹⁾	μA
		-	-		450 (average) ⁽¹⁾	μA
V_{AIN}	Conversion voltage range	-	0 ⁽²⁾	-	V_{REF+}	V
T_A	Temperature range	-	-40	-	125	$^{\circ}\text{C}$
R_{AIN}	External resistance on V_{AIN}	on PF0 fast channel	-	-	50 ⁽³⁾	$\text{k}\Omega$
		on all other channels	-	-		
C_{ADC}	Internal sample and hold capacitor	on PF0 fast channel	-	16	-	pF
		on all other channels	-		-	
f_{ADC}	ADC sampling clock frequency	$2.4\text{ V} \leq V_{DDA} \leq 3.6\text{ V}$ without zooming	0.320	-	16	MHz
		$1.8\text{ V} \leq V_{DDA} \leq 2.4\text{ V}$ with zooming	0.320	-	8	MHz
f_{CONV}	12-bit conversion rate	V_{AIN} on PF0 fast channel	-	-	1 ⁽⁴⁾⁽⁵⁾	MHz
		V_{AIN} on all other channels	-	-	760 ⁽⁴⁾⁽⁵⁾	kHz
f_{TRIG}	External trigger frequency	-	-	-	t_{conv}	$1/f_{ADC}$
t_{LAT}	External trigger latency	-	-	-	3.5	$1/f_{SYSCLK}$

Figure 38. ADC1 accuracy characteristics

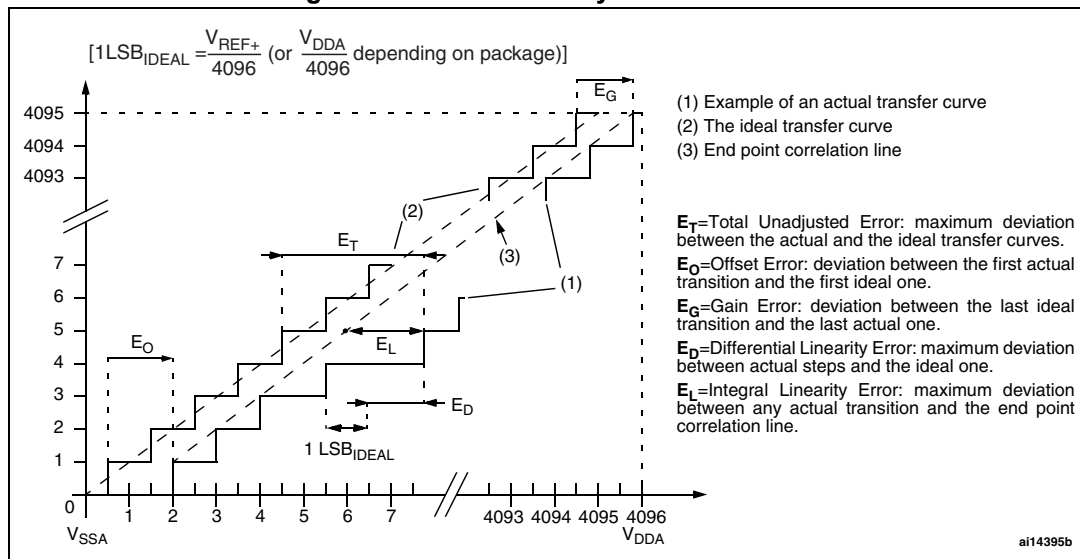
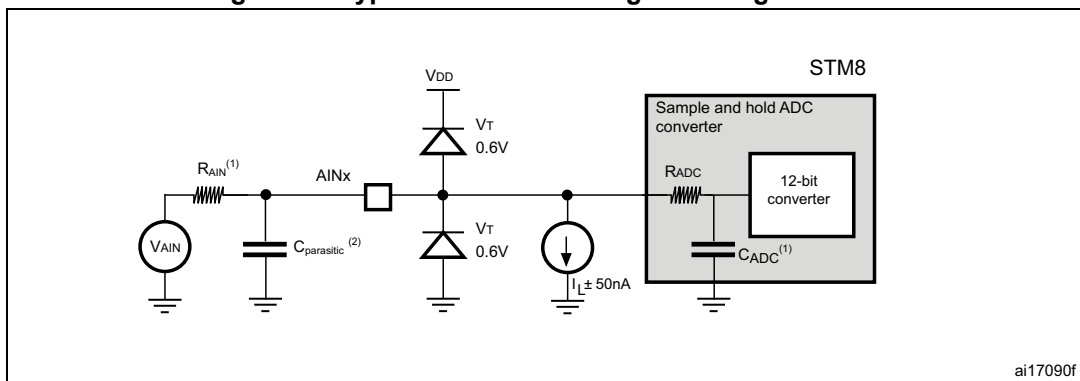


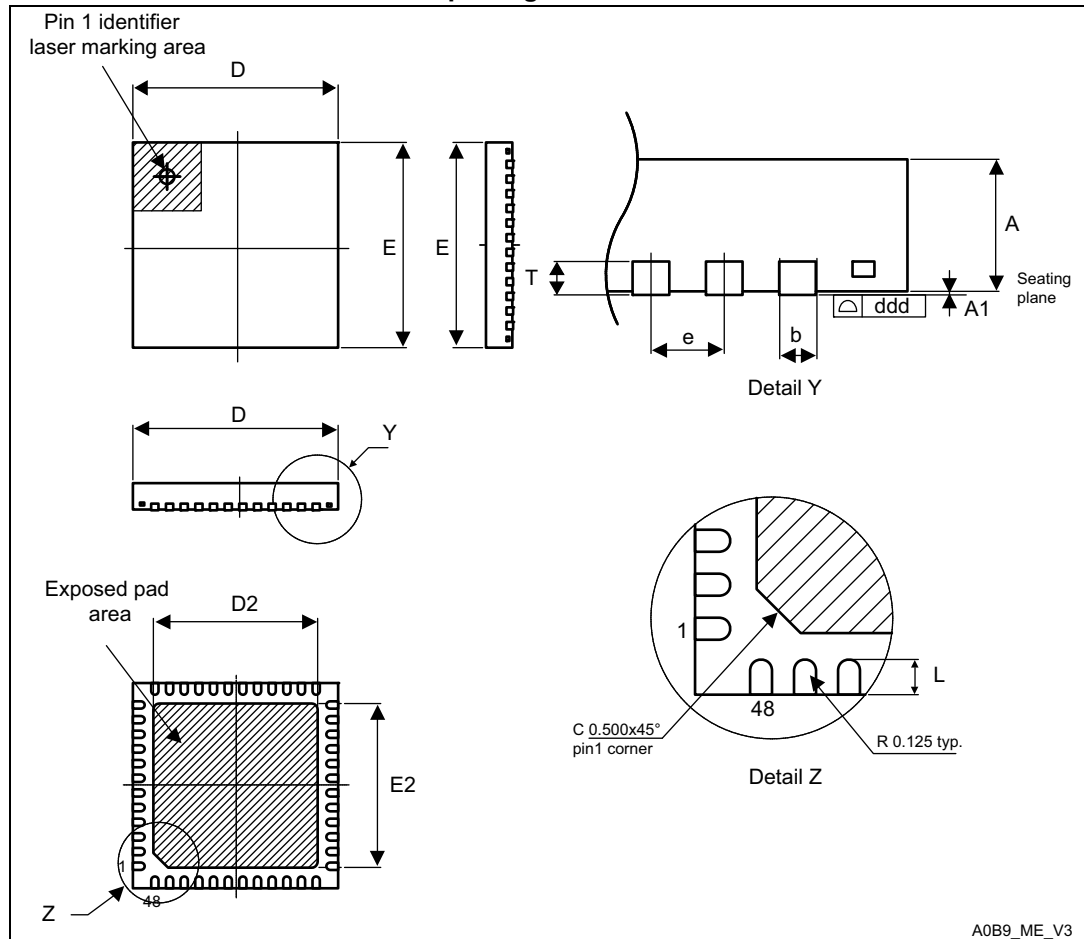
Figure 39. Typical connection diagram using the ADC



1. Refer to [Table 53](#) for the values of R_{AIN} and C_{ADC} .
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high $C_{parasitic}$ value will downgrade conversion accuracy. To remedy this, f_{ADC} should be reduced.

10.3 UFQFPN48 package information

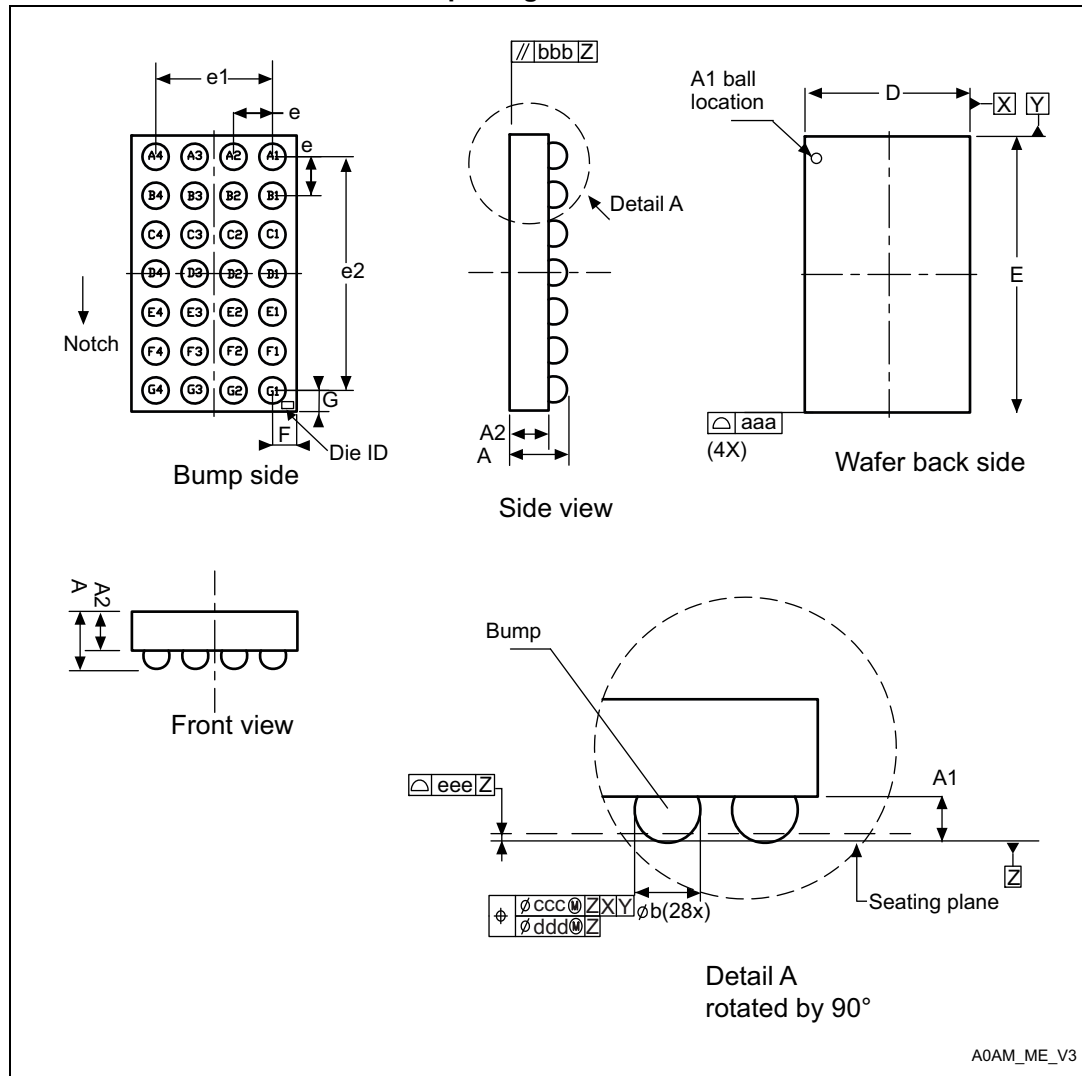
Figure 46. UFQFPN48 - 48-lead, 7 x 7 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package outline



1. Drawing is not to scale.
2. All leads/pads should also be soldered to the PCB to improve the lead/pad solder joint life.
3. There is an exposed die pad on the underside of the UFQFPN package. It is recommended to connect and solder this back-side pad to PCB ground.

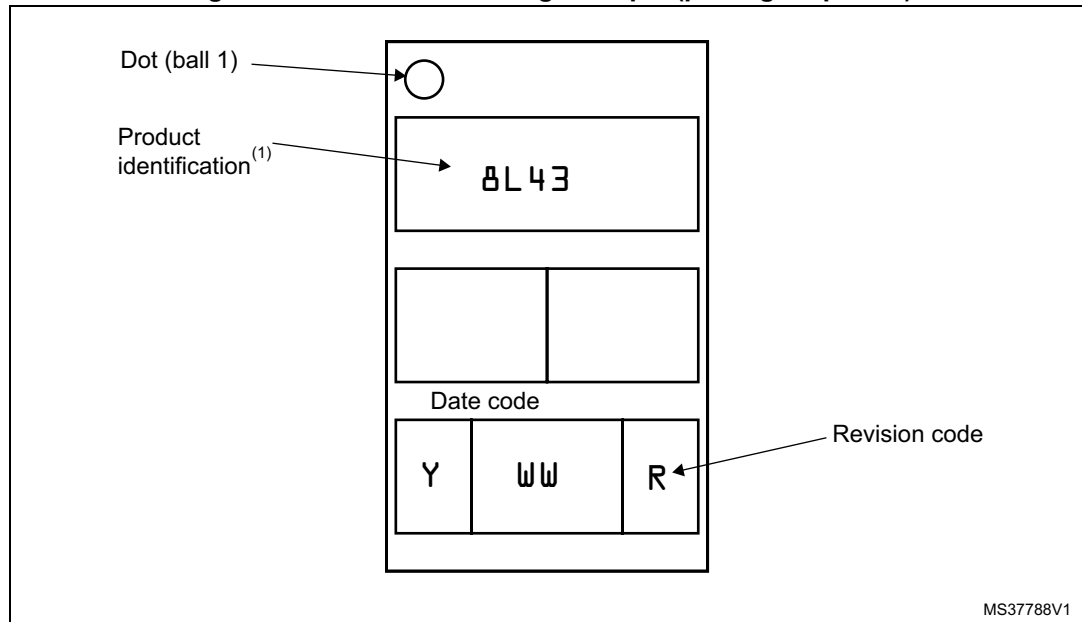
10.7 WLCSP28 package information

Figure 58. WLCSP28 - 28-pin, 1.703 x 2.841 mm, 0.4 mm pitch wafer level chip scale package outline



1. Drawing is not to scale.

Figure 59. WLCSP28 marking example (package top view)

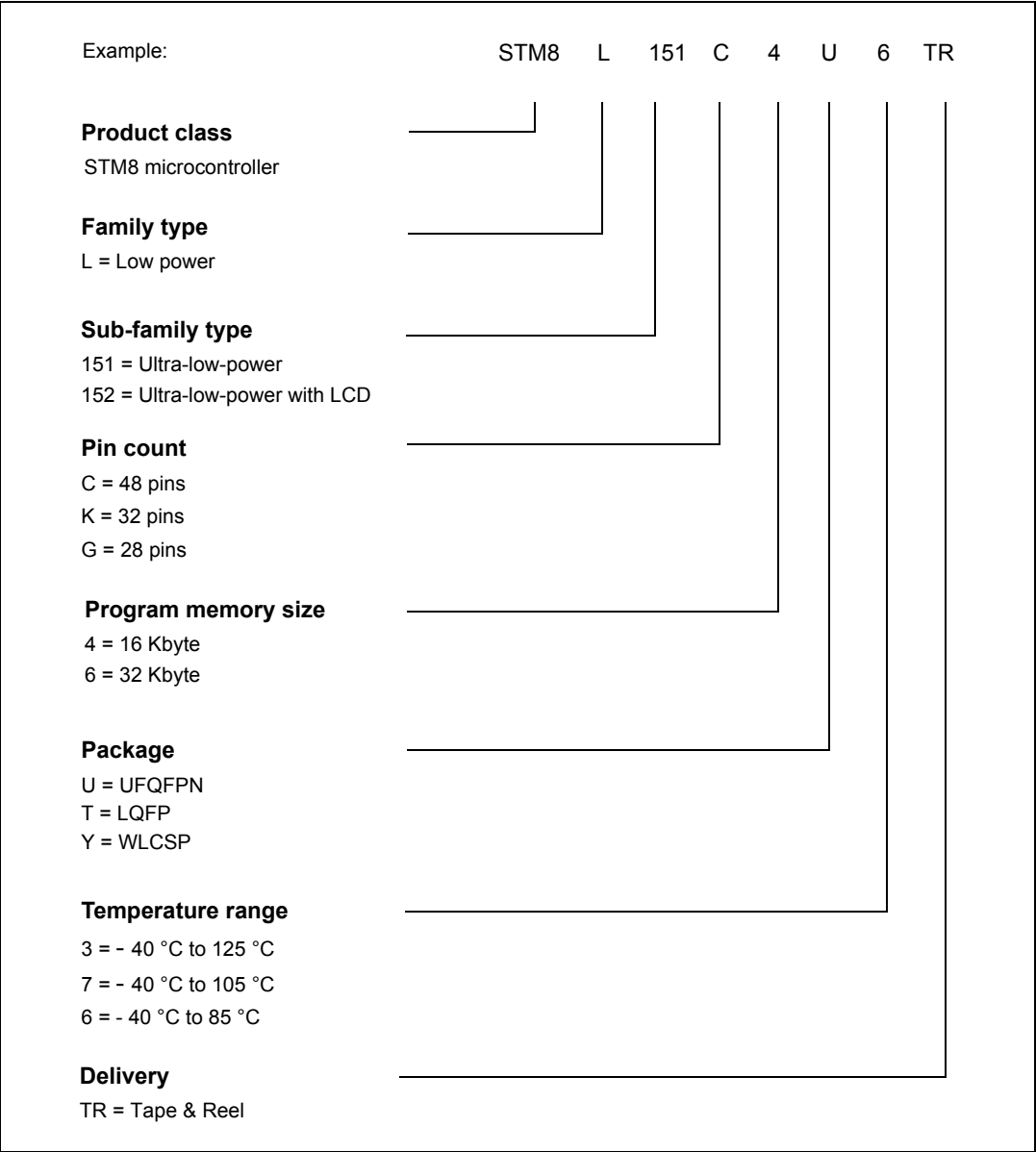


1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

11 Part numbering

For a list of available options (memory, package, and so on) or for further information on any aspect of this device, please contact your nearest ST sales office.

Figure 60. Medium-density STM8L15x ordering information scheme



1. For a list of available options (e.g. memory size, package) and orderable part numbers or for further information on any aspect of this device, please contact the ST sales office nearest to you.

